## Notice of References Cited

Application/Control N 10/786,701	o. Applicant(s)/Pate Reexamination HUANG ET AL.			
Examiner	Art Unit			
N. Drew Richards	2815	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0025154	02-2003	Haynie, Sheldon D.	257/335
	В	US-2001/0038122	11-2001	Matsuzaki et al.	257/339
	С	US-2003/0042541	03-2003	Rumennik et al.	257/343
	D	US-2003/0067036	04-2003	Depetro et al.	257/335
	Ε	US-2003/0193067	10-2003	Kim et al.	257/343
	F	US-5,155,562 A	10-1992	Tsuchiya, Kazuhiro	257/343
	G	US-5,932,897 A	08-1999	Kawaguchi et al.	257/141
	Н	US-6,424,005	07-2002	Tsai et al.	257/335
	-	US-6,160,290	12-2000	Pendharkar et al.	257/339
	J	US-6,492,679	12-2002	Imam et al.	257/342
	К	US-6,756,636 B2	06-2004	Onishi et al.	257/342
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				* *	
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.